

Search Notes

Application/Control No.

10/624,670

Examiner

Shin-Lin Chen

Applicant(s)/Patent under
Reexamination

LI ET AL.

Art Unit

1632

SEARCHED

Class	Subclass	Date	Examiner
424	93.2		
536	23.1		
536	24.1		
435	320.1		
435	455	10/17/2007	SLC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
424	93.2		
435	320.1		
435	455		
536/23.1, 24.1, AU interference search		10/17/2007	SLC

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated, inventor name search.	10/17/2007	SLC